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N-Channel 650V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY							
V _{DS} (V) at T _J max.	650						
R _{DS(on)} max. at 25 °C (Ω)	$V_{GS} = 10 V$	0.42					
Q _g max. (nC)	38						
Q _{gs} (nC)	4						
Q _{gd} (nC)	4.2						
Configuration	Single						

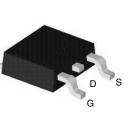
FEATURES

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

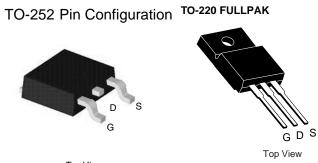
APPLICATIONS

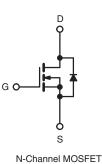
- · Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial





Top View





PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	650	V	
Gate-Source Voltage	V _{GS}	± 30	V			
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	T _C = 25 °C	- I _D -	11		
		T _C = 100 °C		9.7	А	
Pulsed Drain Current ^a		I _{DM}	55			
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	132	mJ	
Maximum Power Dissipation			P _D	83/83/31	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope	T _J = 125 °C		-11 (/ - 11	50		
Reverse Diode dV/dt d	dV/dt	3.1	V/ns			
Soldering Recommendations (Peak Temperature) ^c	for	10 s		300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature.

b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4.5 A.

1.6 mm from case. c.

d. $I_{SD} \leq I_D$, dI/dt = 100 A/µs, starting T_J = 25 °C.





DTU11N65SJ/DTP11N6) SJ/DTP11N6) FSJ www.din-tek.jp

$ \begin{array}{ c c c c c c } \hline PARAMETER & SYMBOL & TYP. MAX. UNIT \\ \hline Maximum Junction-to-Ambient & R_{m,A} & - & 60 \\ \hline Maximum Junction-to-Case (Drain) & R_{m,O} & - & 0.6 \\ \hline \\ $	THERMAL RESISTANCE RATINGS											
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TYP.		MAX.		UNIT					
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Ambient	R _{thJA}					°C 0.0					
$\begin{array}{ c c c c c } \hline PARAMETER SYMBOL SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$	Maximum Junction-to-Case (Drain)	R _{thJC}					°C/W					
$\begin{array}{ c c c c c } \hline PARAMETER SYMBOL SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$												
	SPECIFICATIONS (T _J = 25 °C, unless otherwise noted)											
$\begin{array}{ c c c c c c } \hline Drain-Source Breakdown Voltage V_{DS} & $V_{QS} = 0 V, $l_{D} = 250 \ \mu A$ & 650 & - $ & V V/C$ \\ \hline V_{DS} Temperature Coefficient $\Delta V_{DS} T_J$ & Reference to 25 °C, $l_{D} = 1 \ m A$ & - $ & 0.65 & - $ & V'/C \\ \hline Gate-Source Threshold Voltage (N) $V_{OS} W$ & $V_{DS} = V_{S}, $l_{D} = 250 \ \mu A$ & 2 & - $ & 4 & V \\ \hline Gate-Source Leakage I_{QSS} & $V_{QS} = 20V$ & - $ & - $ & 110 & nA \\ \hline V_{QS} = $ $20V$ & $-$ & $-$ & 11 & μA \\ \hline V_{QS} = $ $20V$ & $V_{CS} = $ $20V$ & $-$ & $-$ & 11 & μA \\ \hline V_{DS} = $ $650V$, $V_{QS} = 0V$ & $-$ & $-$ & 10 & $-$ & 11 & μA \\ \hline Drain-Source On-State Resistance $R_{DS(en)}$ & $V_{DS} = $30V$ $l_{D} = $5A$ & $-$ & 0.42 & $-$ & Ω \\ \hline Porward Transconductance g_{16} & $V_{DS} = $30V$, $l_{D} = $5A$ & $-$ & 16 & $-$ & S \\ \hline Dynamic $V_{DS} = $10V$ & $l_{D} = $5A$ & $-$ & 16 & $-$ & S \\ \hline Duput Capacitance C_{DSS} & $V_{DS} = $0V$, $l_{D} = $5A$ & $-$ & 16 & $-$ & S \\ \hline Porward Transconductance, Energy $C_{0(e)}$ \\ \hline Reverse Transfer Capacitance, Chergy $C_{0(e)}$ \\ \hline Reteres Transfer Capacitance, Chergy $C_{0(e)}$ \\ \hline Related Δ^{0} \\ \hline Total Capacitance, Time $C_{0(f)}$ \\ \hline Cotign Charge Q_{0g} \\ \hline Gate-Drain Charge Q_{0g} \\ \hline Gate-Drain Charge Q_{0g} \\ \hline Fall Time t_{1} \\ \hline Tum-Ofn Delay Time $t_{0(e)}$ \\ \hline Fall Time t_{1} \\ \hline Tum-Ofn Delay Time $t_{0(e)}$ \\ \hline Fall Time t_{1} \\ \hline Continuous Source-Drain Diode Current t_{1} \\ \hline MOSFET symbol $showing the $integral reverse $P < t_{1} 11 3 \\ \hline Tum-Source Body Diode Characteristics V_{DS} \\ \hline Pondic $V_{DS} = 5A$, $V_{DS} = $0V$ \\ \hline Pondic $V_{DS} = $0V$, $l_{P} = $5A$, $V_{DS} = 0.0 \\ \hline Tum-Ofn Delay Time t_{1} \\ \hline Pulsed Diode Forward Current t_{1} \\ \hline MOSFET symbol $showing the $integral reverse $P $-$ 11 $$ V \\ \hline Peverse Recovery Time t_{1} \\ \hline Pulsed Diode Forward Current t_{1} \\ \hline MOSFET symbol $showing the $integral reverse $P $-$ 15 $$ V \\ \hline Peverse Recovery Time t_{1} \\ \hline Pulsed Diode Forward Cu$	PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static		-									
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D =	250 µA	650	-	-	V			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	, I _D = 1 mA	-	0.65	-	V/°C			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $					-	-	± 100	nA				
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Leakage	I _{GSS}			-	-	± 1	μA				
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$					-	-	1	μA				
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate Voltage Drain Current	I _{DSS}			-	-	10					
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source On-State Resistance	R _{DS(on)}				-	0.42	-	Ω			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance		V _{DS}	= 30 V, I _D	= 5 A	-	16	-	S			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic						•		L			
$ \begin{array}{ c c c c c } \hline \text{Output Capacitance} & C_{oss} & V_{DS} = 100 \text{ V}, & - & 140 & - & \\ \hline \text{Reverse Transfer Capacitance} & C_{rss} & & & \\ \hline \text{Ffective Output Capacitance, Energy} & C_{o(er)} & & & \\ \hline \text{Effective Output Capacitance, Time} & C_{o(tr)} & & & \\ \hline \text{Related }^{b} & & & \\ \hline \text{Cotal Gate Charge} & Q_{g} & & \\ \hline \text{Cotal Gate Charge} & Q_{gg} & Q_{gg} & \\ \hline \text{Cate-Source Charge} & Q_{gg} & Q_{gg} & \\ \hline \text{Cate-Drain Charge} & Q_{gg} & & \\ \hline \text{Cate-Drain Charge} & Q_{gg} & & \\ \hline \text{Cate-Drain Charge} & Q_{gg} & & \\ \hline \text{Turn-OD Delay Time} & t_{d(off)} & & \\ \hline \text{Rise Time} & t_{r} & \\ \hline \text{Turn-OD Delay Time} & t_{d(off)} & & \\ \hline \text{Fail Time} & & t_{r} & \\ \hline \text{Continuous Source-Drain Diode Current} & I_{S} & & \\ \hline \text{MOSFET symbol} & & \\ \hline \text{Showing the} & & \\ & & & & \\ & & & & \\ \hline \text{ntegral reverse} & & \\ \hline \text{Pulsed Diode Forward Current} & I_{S} & & \\ \hline \text{Riverse Recovery Time} & t_{r} & \\ \hline \text{Riverse Recovery Charge} & Q_{Gr} & & \\ \hline \text{Riverse Recovery Charge} & Q_{Gr} & & \\ \hline \text{Riverse Recovery Charge} & Q_{Gr} & & \\ \hline \text{Riverse Recovery Charge} & Q_{Gr} & & \\ \hline \text{Riverse Recovery Charge} & Q_{rr} & \\ \hline \text{Riverse Recovery Charge} & Q_{rr} & \\ \hline \text{Riverse Recovery Charge} & Q_{rr} & \\ \hline \text{Riverse Recovery Charge} & C_{rr} & \\ \hline \text{Riverse Recovery Charge} & Q_{rr} & \\ \hline \text{Riverse Recovery Charge} & C_{rr} & \\ \hline \text{Riverse Recovery Charge} & \hline \text{Riverse Recovery Charge} & \\ \hline \text{Riverse Recovery Charge} & \hline \text{Riverse Recovery Charge} & \\ \hline \text{Riverse Recovery Charge} & \hline \text{Riverse Recovery Charge} & \\ \hline \text{Riverse Recovery Charge} & \\ \hline \text{Riverse Recovery Charge} & \hline \text{Riverse Riverse Recovery Charge} & \hline \text{Riverse Recovery Charge} & \hline Ri$	Input Capacitance	C _{iss}	$V_{DS} = 100 V,$		-	680	-	pF				
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Output Capacitance	C _{oss}			-	140	-					
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}			-	5	-					
$\begin{array}{c c c c c c c c } \hline \mbox{Hective Output Capacitance, I ime} & C_{0(tr)} & & & & & & & & & & & & & & & & & & &$		C _{o(er)}	$V_{DS} = 0 V $ to 520 V, $V_{GS} = 0 V$		-	63	-					
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		C _{o(tr)}			-	113	-					
$\begin{tabular}{ c c c c c c } \hline Gate-Drain Charge & Q_{gd} & $-$ & 4.5 & $-$ \\ \hline Turn-On Delay Time & $t_{d(on)}$ \\ \hline Rise Time & t_{r} & $V_{DD} = 520 \ V, \ I_D = 5 \ A,$ \\ $V_{GS} = 10 \ V, \ R_g = 9.1 \ \Omega$ & $-$ & 11 & 35 \\ \hline -$ & 81 & 90 \\ \hline -$ & 25 & 40 \\ \hline \\ \hline \\ \hline \\ Gate \ Input \ Resistance & R_g & $f = 1 \ MHz, \ open \ drain & $-$ & 3.5 & $-$ & Ω \\ \hline \\ \hline \\ \hline \\ \hline \\ Drain-Source \ Body \ Diode \ Characteristics & $$V_{GS} = 10 \ V, \ R_g = 9.1 \ \Omega$ & $-$ & 3.5 & $-$ & Ω \\ \hline \\ \hline \\ \hline \\ \hline \\ \hline \\ \hline \\ Gate \ Input \ Resistance & R_g & $f = 1 \ MHz, \ open \ drain & $-$ & 3.5 & $-$ & Ω \\ \hline \\ $	Total Gate Charge	Qg				-	38	56				
$\begin{tabular}{ c c c c c } \hline Turn-On Delay Time & t_{d(on)} & & & & & & & & & & & & & & & & & & &$	Gate-Source Charge	*	$V_{GS} = 10 V$ $I_D = 5 A, V_{DS} = 520 V$		A, V _{DS} = 520 V	-	4	-	nC			
Rise Time t_r $V_{DD} = 520 \text{ V}, \text{ I}_D = 5 \text{ A}, V_{GS} = 10 \text{ V}, \text{ R}_g = 9.1 \Omega$ $ 11$ 35 $ 81$ 90 Fall Time t_f t_f $ 25$ 40 $ 25$ 40 Gate Input Resistance R_g $f = 1 \text{ MHz}, \text{ open drain}$ $ 3.5$ $ \Omega$ Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode Current I_S $MOSFET symbol showing the integral reverse p - n junction diode 1135Pulsed Diode Forward VoltageV_{SD}T_J = 25 \ ^{\circ}C, I_S = 5 \text{ A}, V_{GS} = 0 \text{ V} 1.5VReverse Recovery Timet_{rr}T_J = 25 \ ^{\circ}C, I_F = I_S = 5 \text{ A}, dI/dt = 100 \ A/\mu S, V_B = 400 \ V 3.3 \mu \mu$	Gate-Drain Charge	Q_gd				-	4.5	-				
$\begin{array}{c c c c c c c c c c c c c c c c c c c $					-			-				
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		t _r										
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $												
Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode-11APulsed Diode Forward CurrentIsMIsMTJ = 25 °C, IS = 5 A, VGS = 0 V15VDiode Forward VoltageVSDTJ = 25 °C, IS = 5 A, VGS = 0 V1.5VReverse Recovery TimetrrTJ = 25 °C, IF = IS = 5 A, dl/dt = 100 A/µS, VB = 400 V-3.3-µC						-			-			
	•	-	T = 1	winz, ope	n drain	-	3.5	-	Ω			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Body Diode Characteristic	cs				1	1					
Pulsed Diode Forward CurrentIsmIntegra reverse p - n junction diode55Diode Forward Voltage V_{SD} $T_J = 25 \ ^{\circ}C$, $I_S = 5 \ ^{\circ}A$, $V_{GS} = 0 \ ^{\circ}V$ 1.5 V Reverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = I_S = 5 \ ^{\circ}A$, dl/dt = 100 A/µs, $V_R = 400 \ ^{\circ}V$ 1.5 V	Continuous Source-Drain Diode Current	I _S	showing the integral reverse		-	-	11	A				
Reverse Recovery Time t_{rr} -270-nsReverse Recovery Charge Q_{rr} T_J = 25 °C, I_F = I_S = 5 A, dl/dt = 100 A/µs, V_B = 400 V-3.3-µC	Pulsed Diode Forward Current	I _{SM}			-	-	55					
Reverse Recovery Time t_{rr} -270-nsReverse Recovery Charge Q_{rr} T_J = 25 °C, I_F = I_S = 5 A, dl/dt = 100 A/µs, V_B = 400 V-3.3-µC	Diode Forward Voltage	V _{SD}	$T_{\rm J} = 25 \ ^{\circ}{\rm C}, \ I_{\rm S} = 5 \ {\rm A}, \ V_{\rm GS} = 0 \ {\rm V}$		-	-	1.5	V				
Reverse Recovery Charge Q_{rr} $T_J = 25 \ ^{\circ}C, I_F = I_S = 5 \ ^{\circ}A, \\ dI/dt = 100 \ ^{\circ}A/\mu S, V_R = 400 \ ^{\circ}V$ -3.3- μC	Reverse Recovery Time		T _J = 25 °C, I _F = I _S = 5 A,		-	270	-	ns				
di/dt = 100 A/µs, v _R = 400 V	Reverse Recovery Charge				-	3.3	-	μC				
	Reverse Recovery Current	I _{RRM}			-	30	-	-				

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

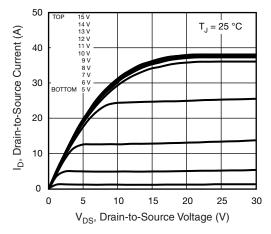


Fig. 1 - Typical Output Characteristics

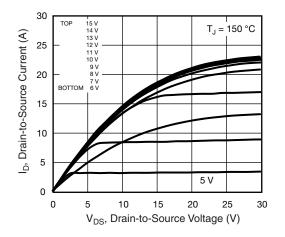


Fig. 2 - Typical Output Characteristics

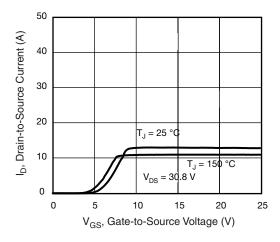


Fig. 3 - Typical Transfer Characteristics

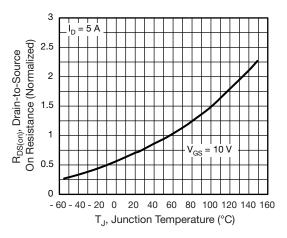


Fig. 4 - Normalized On-Resistance vs. Temperature

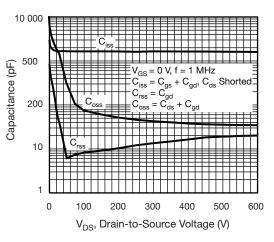


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

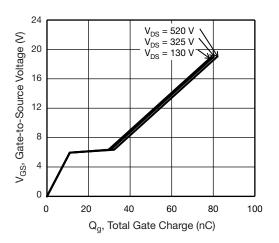


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



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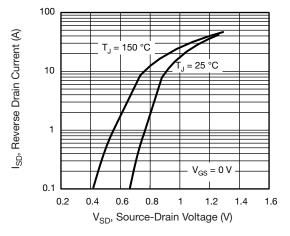
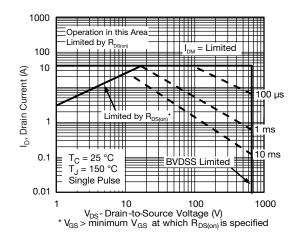


Fig. 7 - Typical Source-Drain Diode Forward Voltage





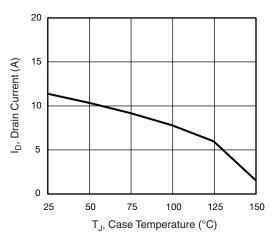


Fig. 9 - Maximum Drain Current vs. Case Temperature

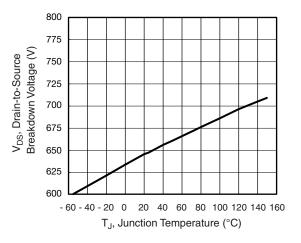


Fig. 10 - Temperature vs. Drain-to-Source Voltage

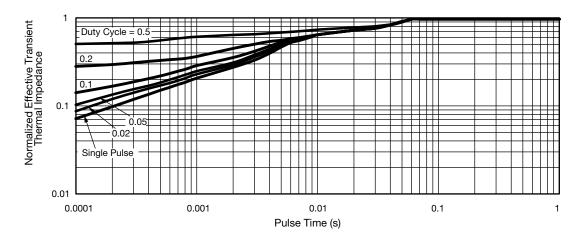


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



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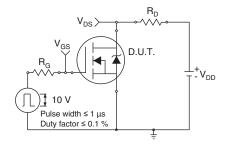


Fig. 12 - Switching Time Test Circuit

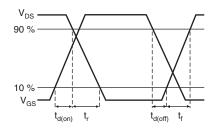


Fig. 13 - Switching Time Waveforms

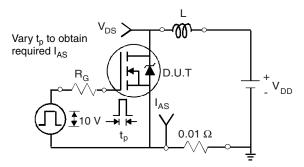


Fig. 14 - Unclamped Inductive Test Circuit

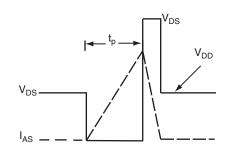


Fig. 15 - Unclamped Inductive Waveforms

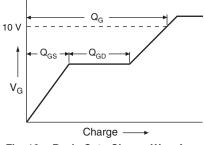


Fig. 16 - Basic Gate Charge Waveform

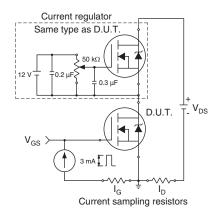
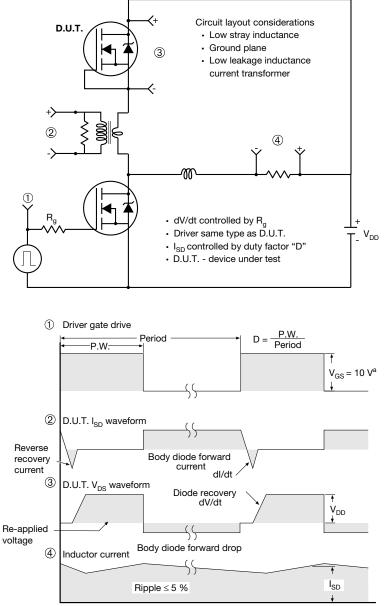


Fig. 17 - Gate Charge Test Circuit



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Note

a. $V_{GS} = 5 V$ for logic level devices

Fig. 18 - For N-Channel



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Please note that some Din-Tek documentation may still make reference to RoHS Directive 2002/95/EC. We confirm that all the products identified as being compliant to Directive 2002/95/EC conform to Directive 2011/65/EU.

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